

The NanoScan VLS-80



• NanoScan •
Switzerland

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The NanoScan VLS-80 The perfect companion for the TOF.SIMS 5

High vacuum AFM with unique TOF.SIMS 5 navigation and sample handling compatibility

Through the combination of AFM topographical information and TOF-SIMS chemical analysis true three-dimensional chemical imaging is now possible. Thanks to its unique navigation software and sample handling compatibility, the NanoScan VLS-80 is the only AFM to fully

complement the TOF.SIMS 5. Finding and analyzing TOF-SIMS acquisition areas and sputter craters is accomplished in a matter of minutes.

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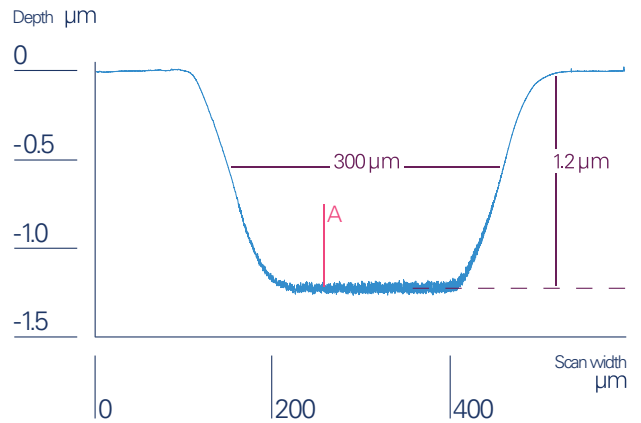
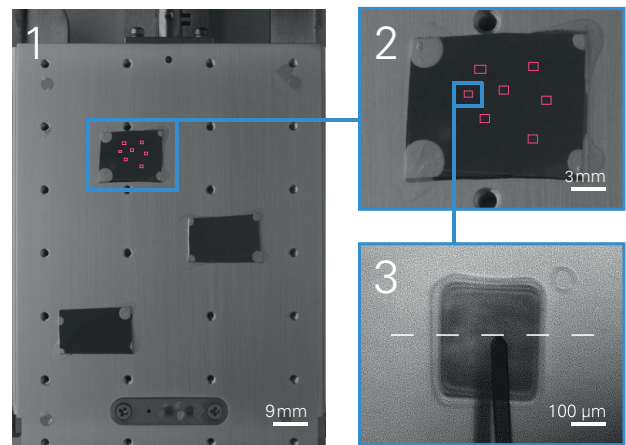
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Combining AFM and TOF-SIMS has never been so fast and easy

The standard TOF-SIMS sample holders can be used directly with the NanoScan VLS-80 and sample position lists can be imported from the SurfaceLab software. Therefore, acquisition areas are easily transferred between the two instruments. Full software compatibility allows AFM and TOF-SIMS data to be combined and analyzed together.

Measuring a sputter crater, even if it is barely visible is straightforward. The crater position is imported to the VLS-80 Navigator, the stage is automatically driven to the selected area and AFM acquisitions can start immediately. Here the "Profiler Mode" or any of the AFM measurement modes come to play, either in air or vacuum.

- 1 Image of a TOFSIMS 5 sample holder with three Si wafer pieces, as displayed in the SurfaceLab Navigator software.
- 2 Optical zoom on a wafer, showing areas where TOF-SIMS acquisitions were performed as magenta boxes.
- 3 Top-view image showing the sputter crater measured along the dotted line using the Profiler Mode below.



Surface profile of the sputter crater shown in image 3.

Contact AFM image measured at position A in the surface profile above.

